

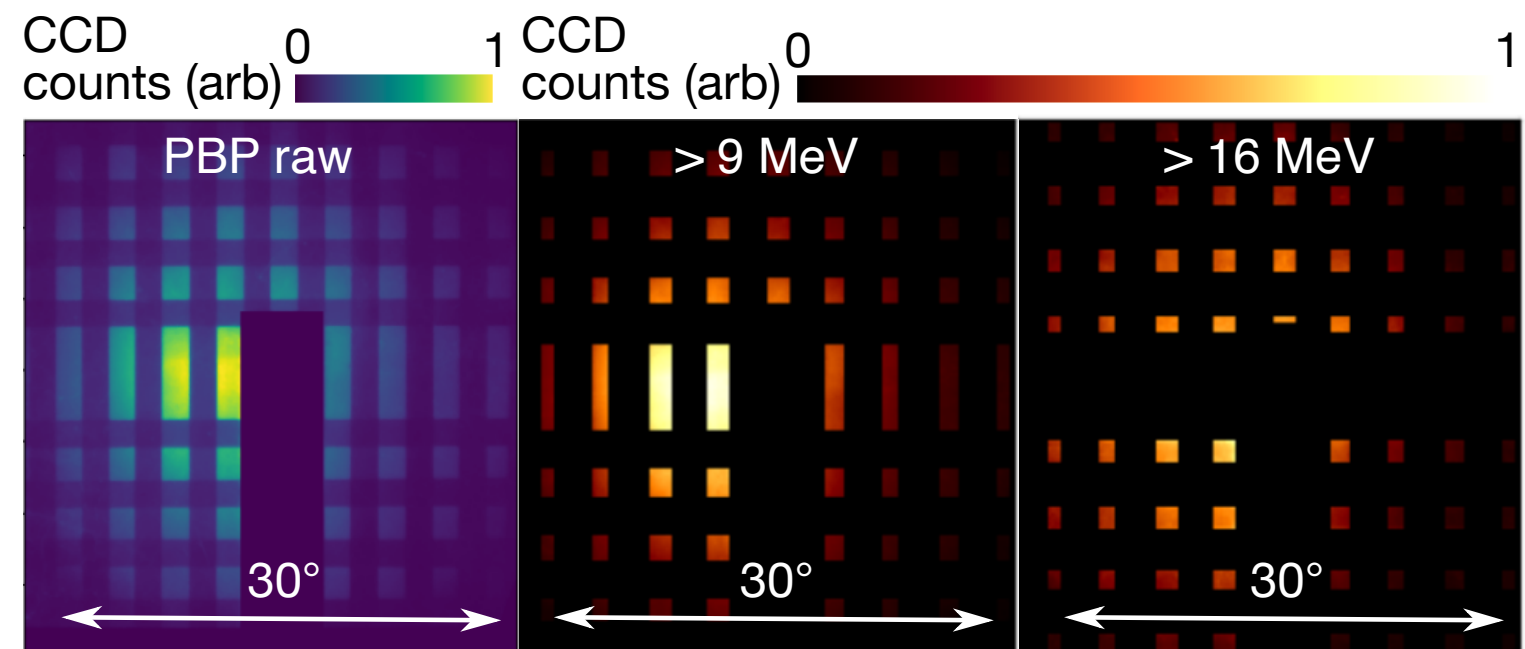
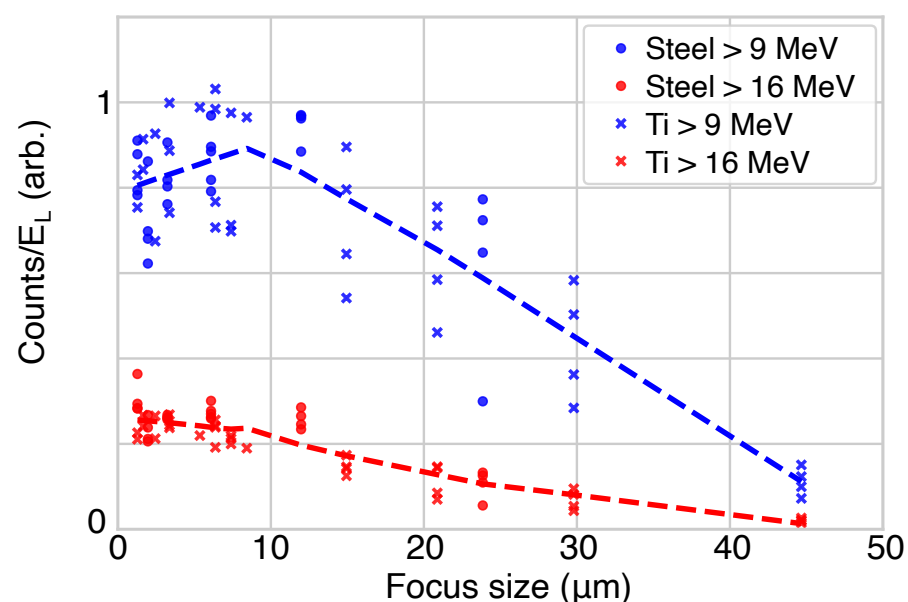
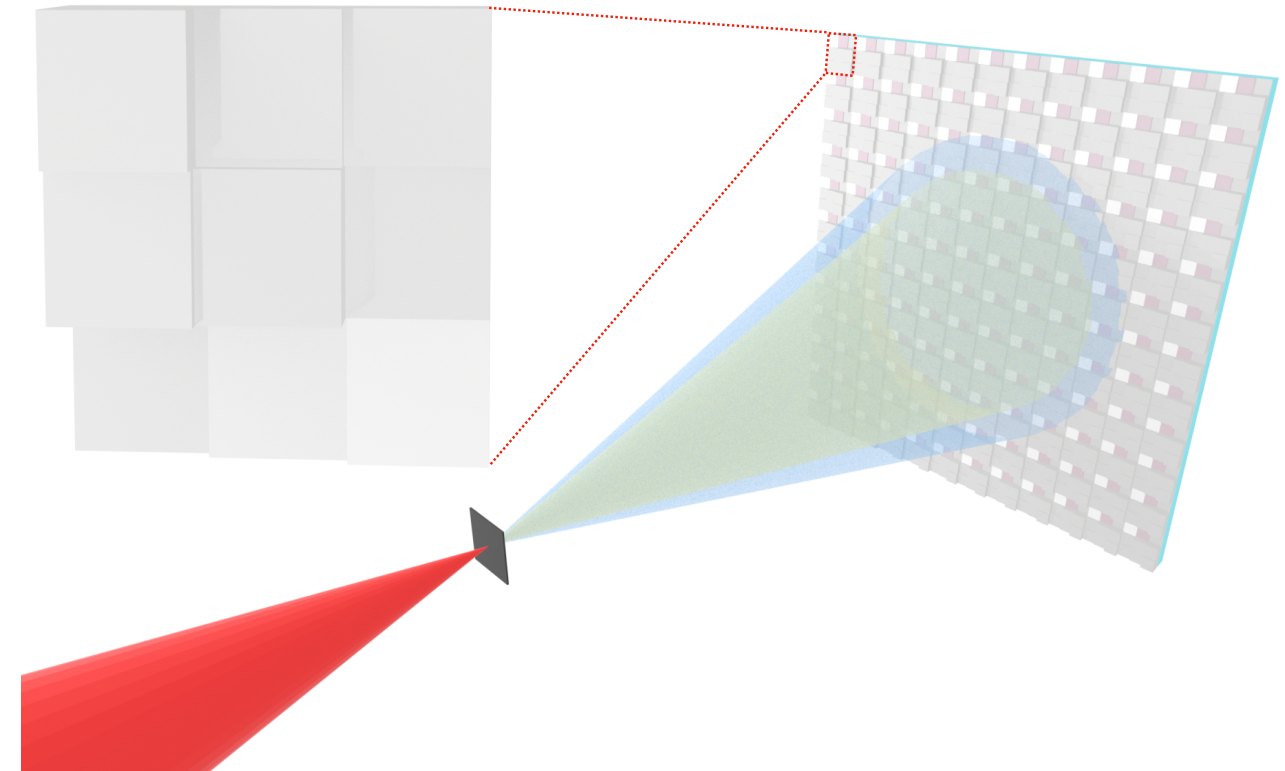
Optimisation of high repetition rate diagnostic design using synthetic modelling

H. Deol, A. Truslove, A. Hussain, N.P. Dover

LhARA Collaboration Meeting #8, 18-19th September 2025

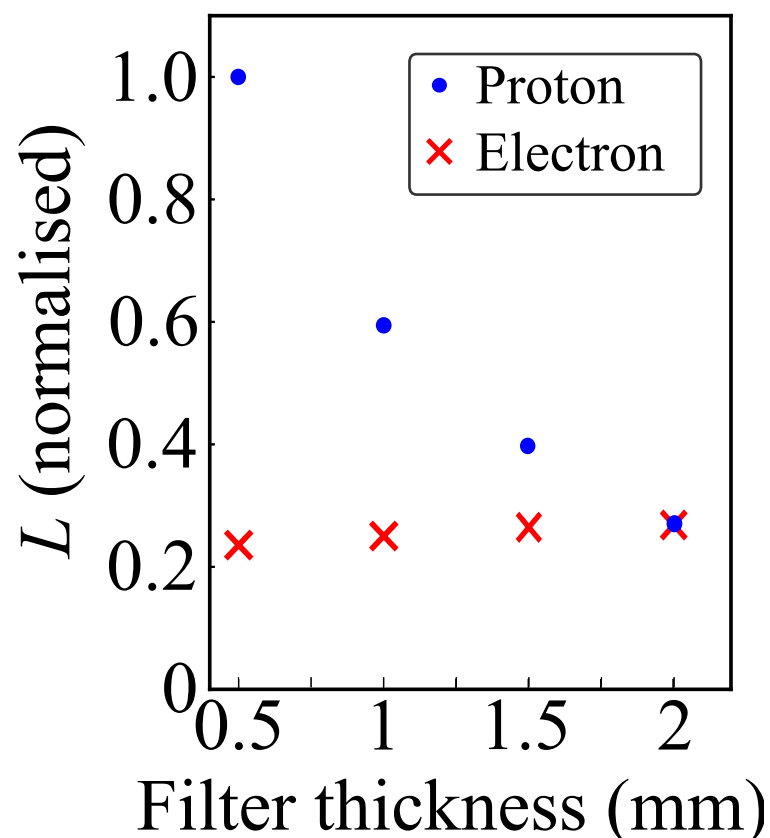
“PROBIES” diagnostic

- High repetition rate alternative to radiochromic film stack
- Differential filtering attenuates beam, visible on scintillator
- Source spectrum reconstruction solved as an inverse problem

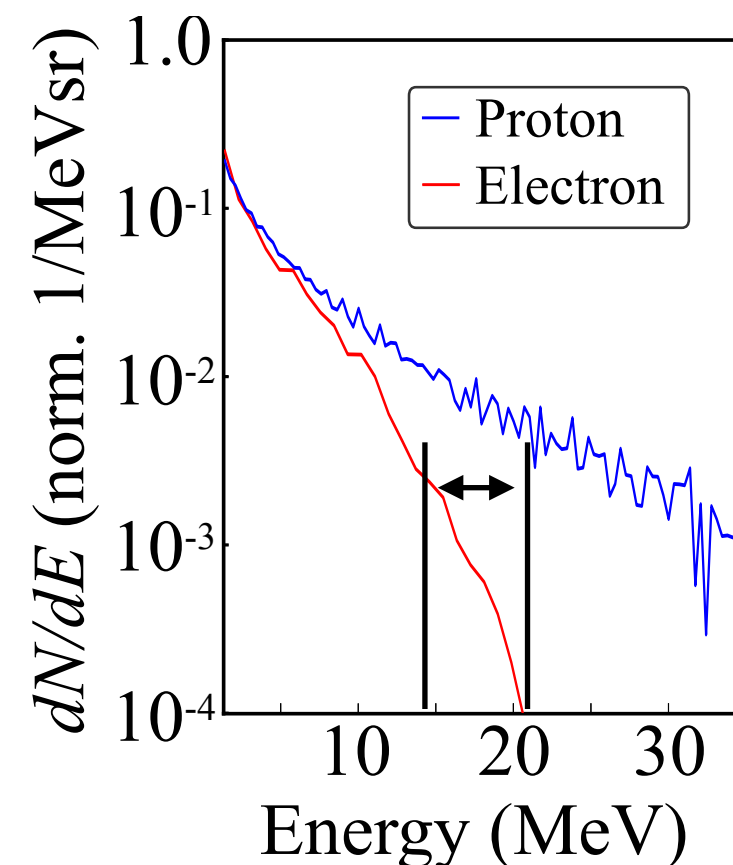


Problems with background

- Laser driven ion sources produce other radiation - relativistic electron beam is a major source of background
- Electrons penetrate through all filters - but most ions don't penetrate thickest filters



Example spectra (from simulation)



Dover+, Review of Scientific Instruments 88, 073304 (2017)

High energy ion spectrum is most susceptible to noise!

Synthetic data & CNN-guided analysis

The challenge:

Solving for the
source spectrum
quickly

Making the best
choice of filter
array thicknesses

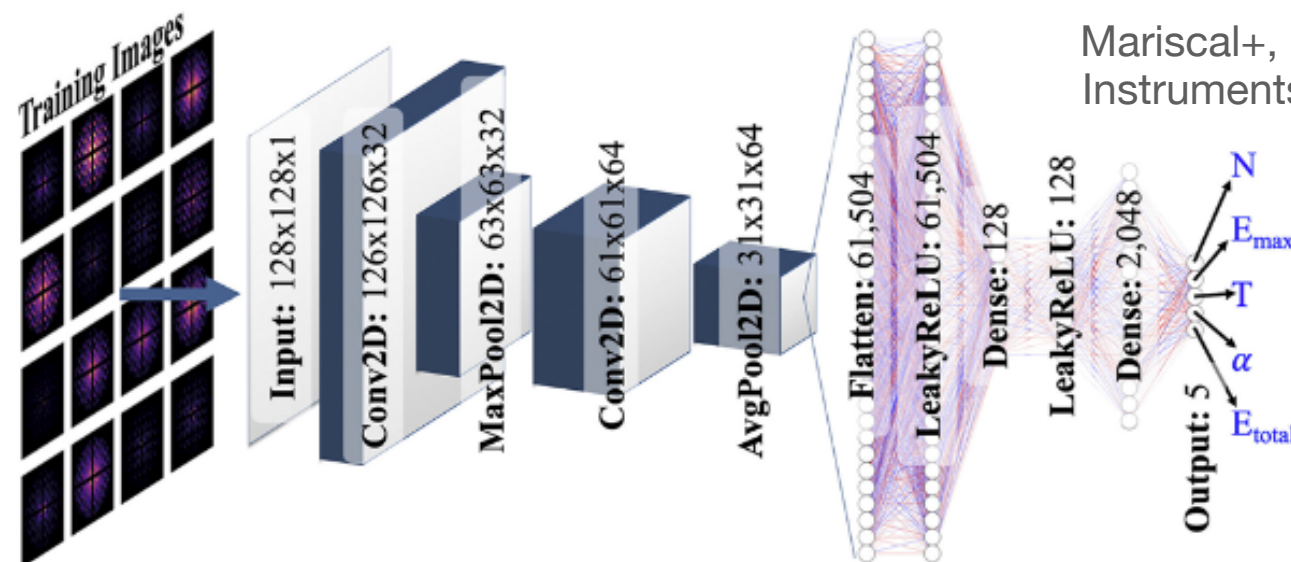
Dealing with
electron
background
robustly

Synthetic data & CNN-guided analysis

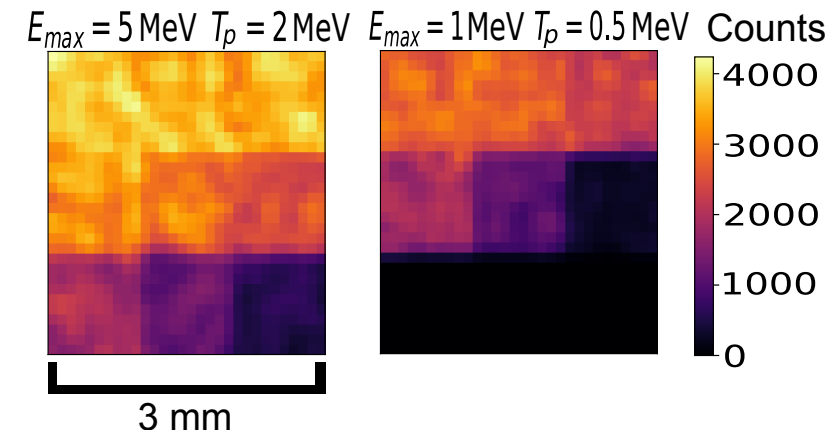
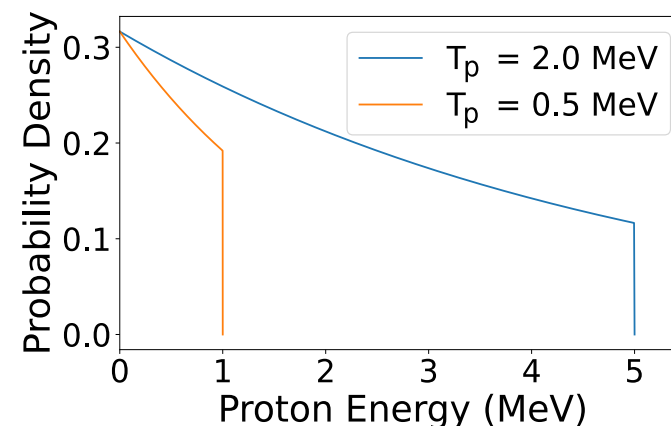
The challenge:

Solving for the
source spectrum
quickly

- Convolutional neural networks turn images into numbers
- Need training data - make a *synthetic diagnostic model*



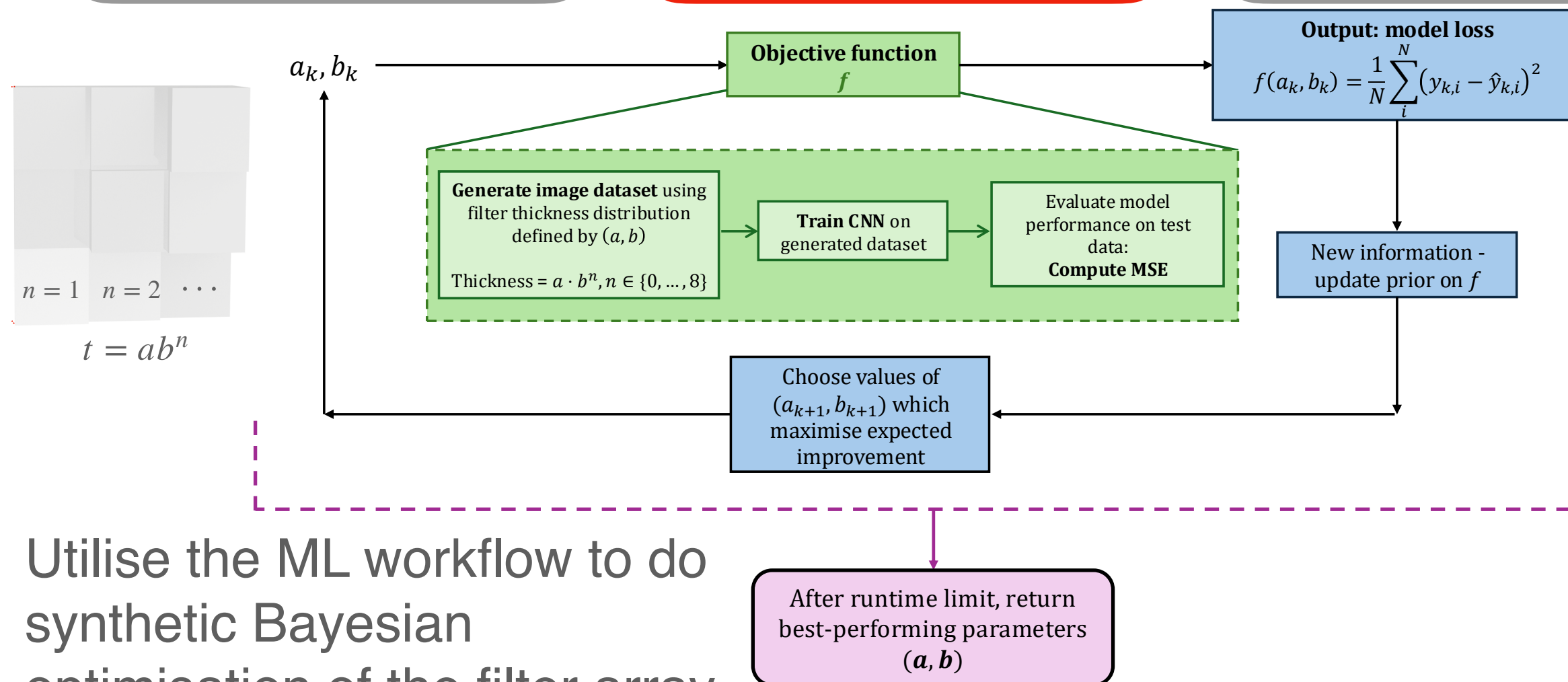
Mariscal+, Review of Scientific Instruments 94, 023507 (2023)



Synthetic data & CNN-guided analysis

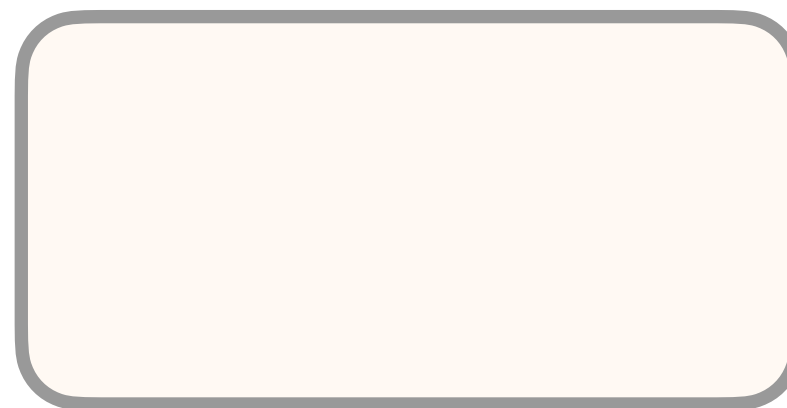
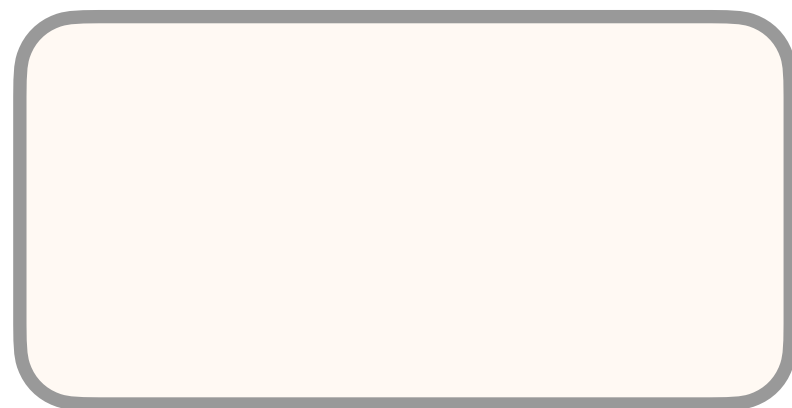
The challenge:

Making the best
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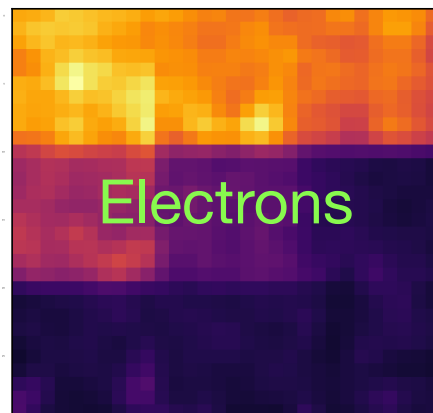
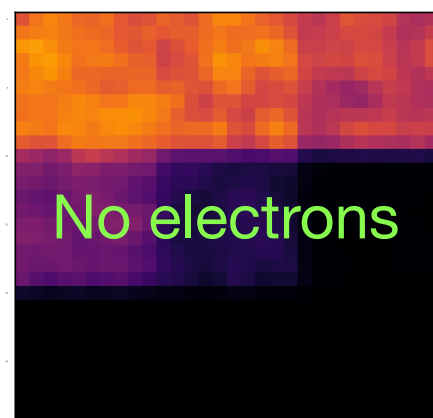
Synthetic data & CNN-guided analysis

The challenge:

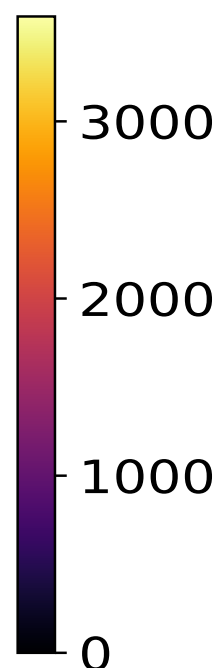


**Dealing with
electron
background
robustly**

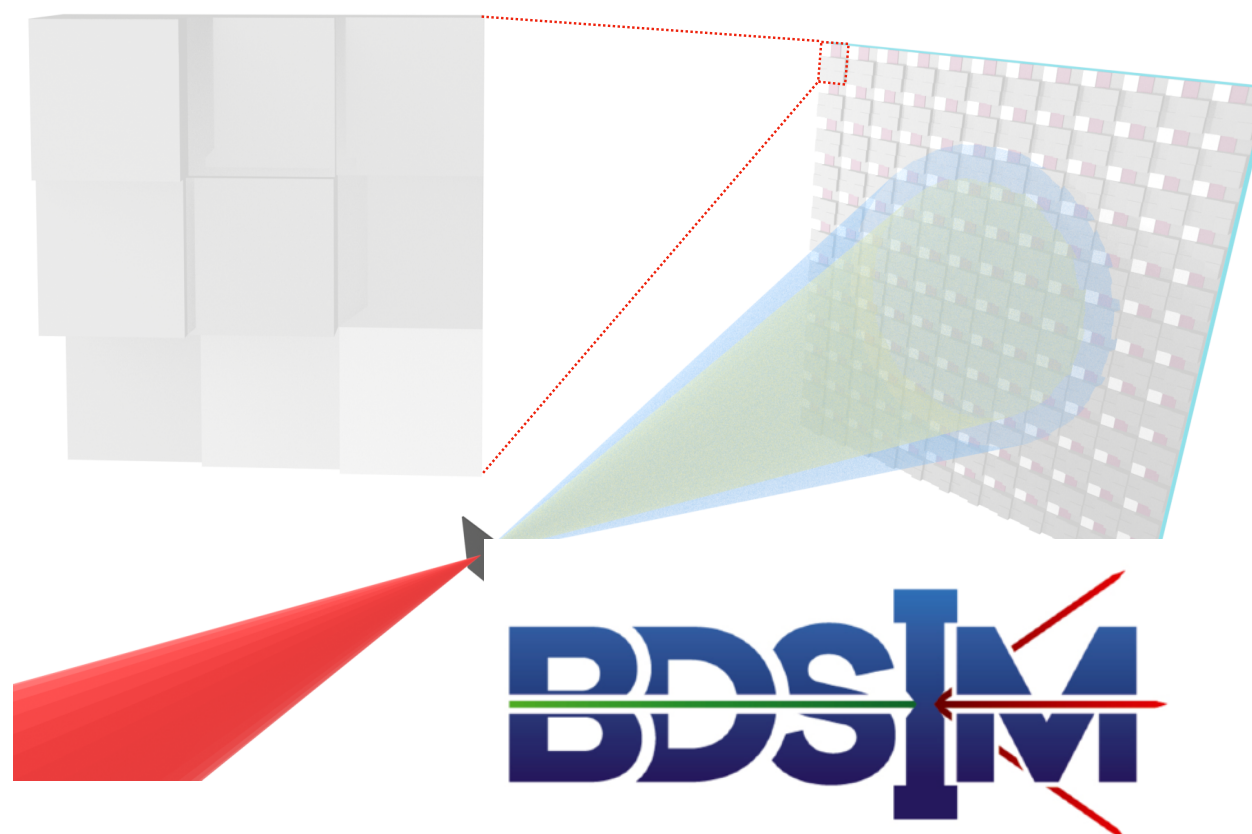
10 Pixels



Counts



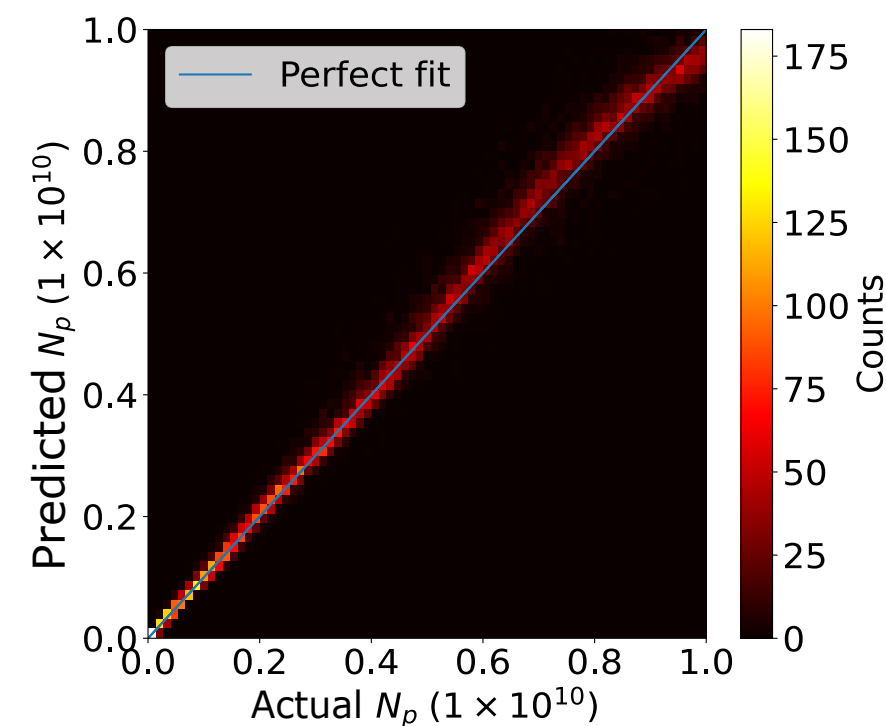
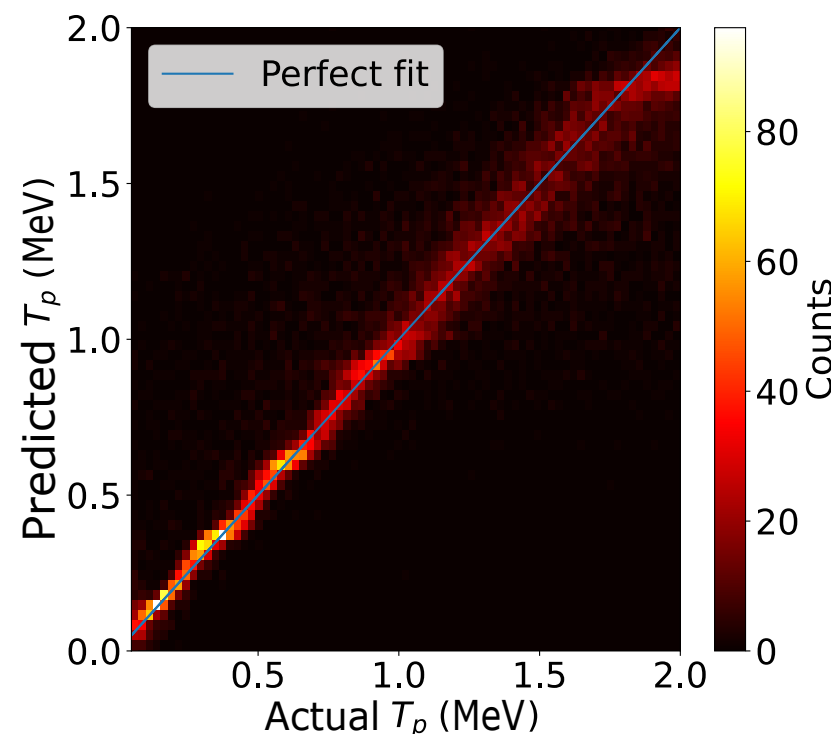
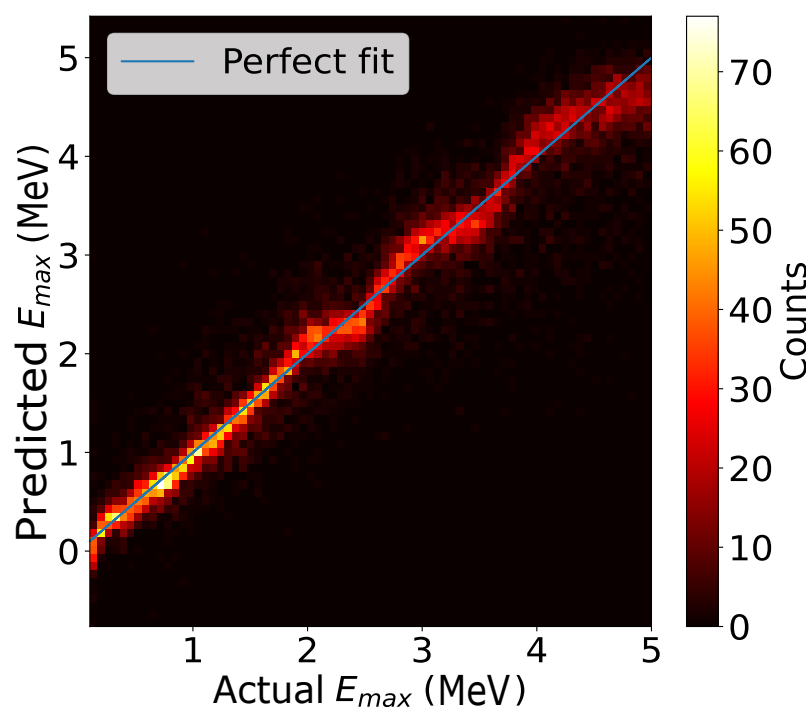
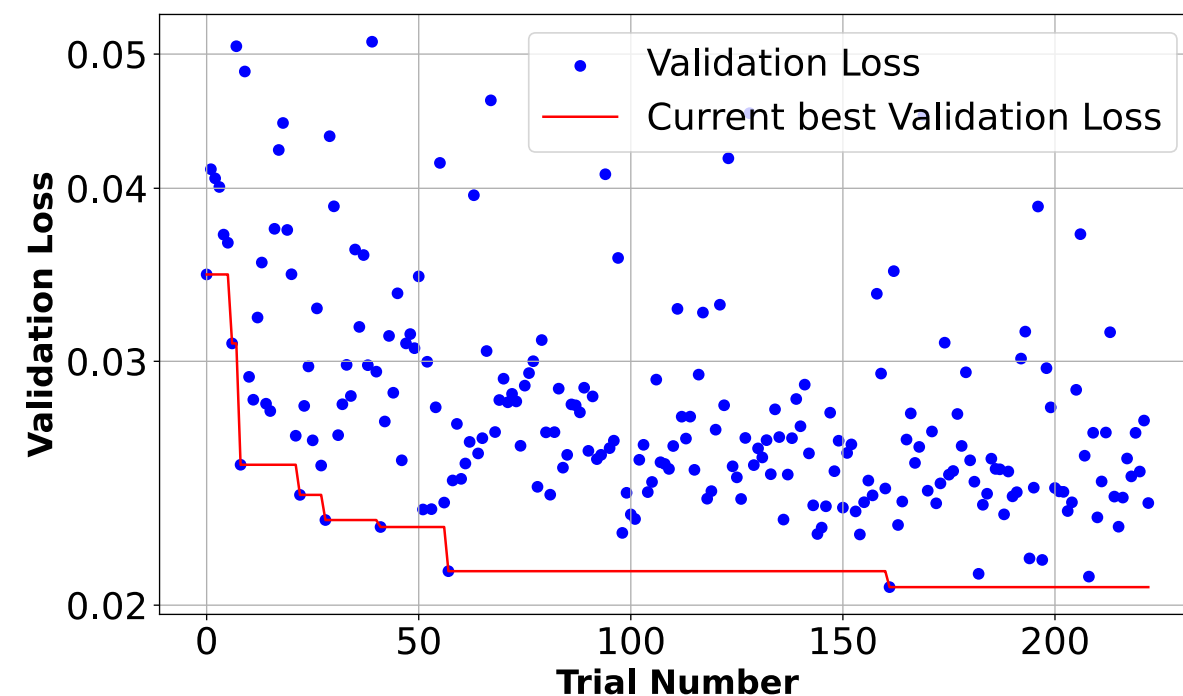
Include varying electron noise as
part of the synthetic dataset



Optimised performance - protons only

- The optimisation loop found a set of thicknesses that minimised the prediction error:

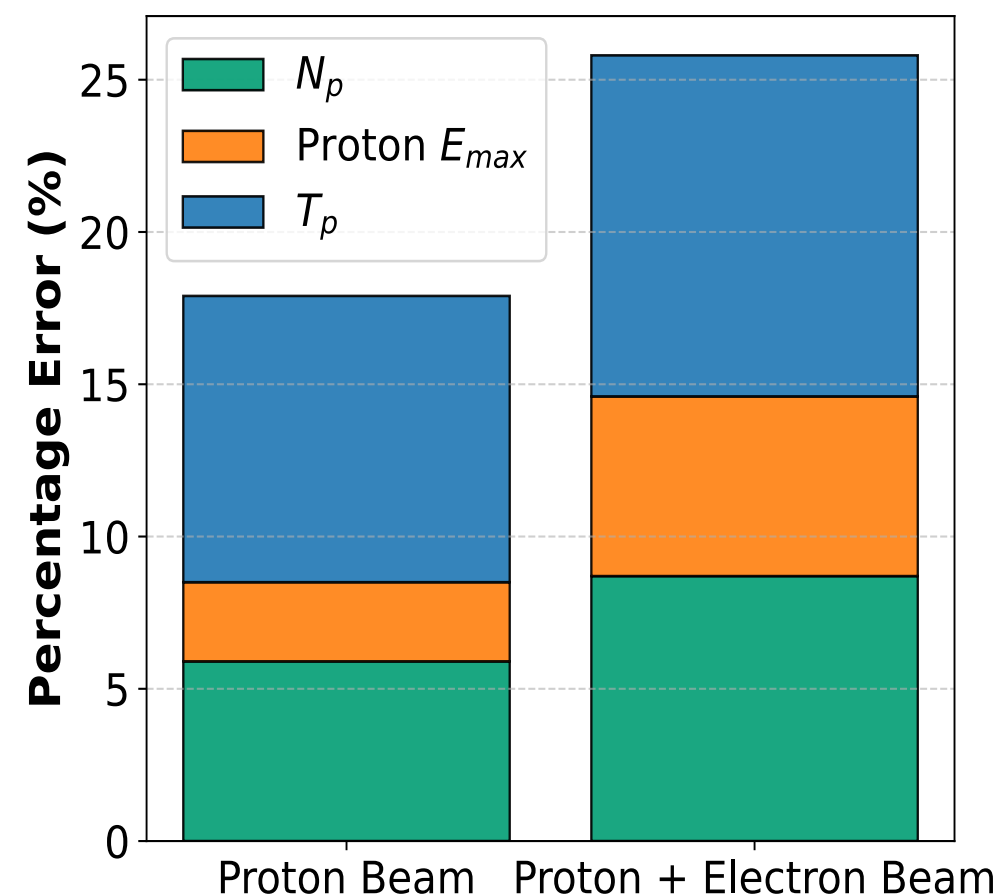
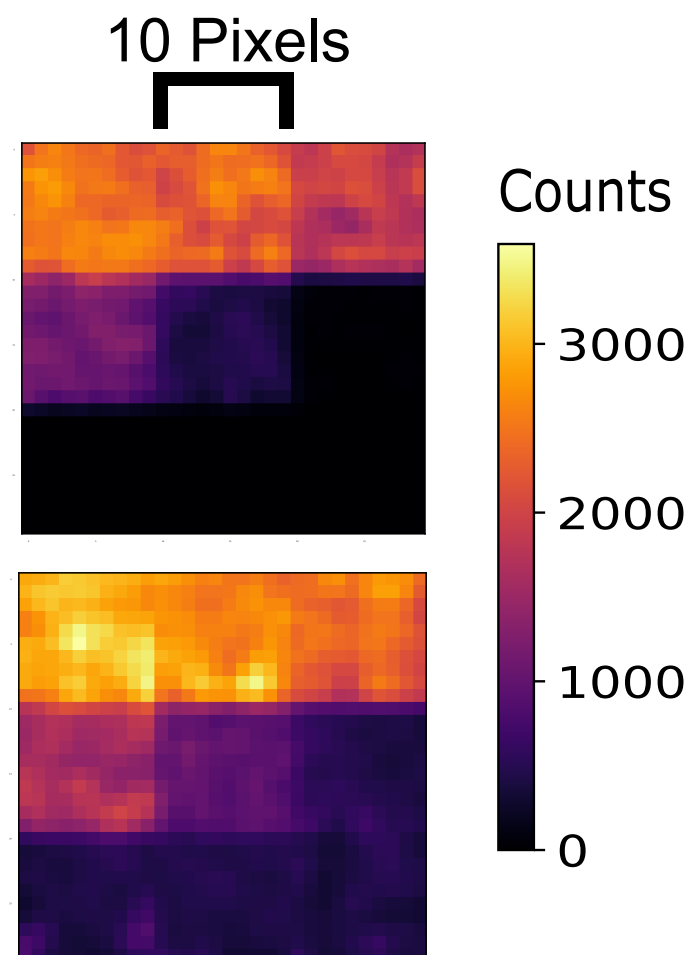
$$\frac{dN}{dE} = \begin{cases} N_p \exp(-E/T_p) & \text{for } E \leq E_{max} \\ 0 & \text{for } E > E_{max} \end{cases}$$



Processing time ~ 5 ms per image on generic laptop

Impact of electron background

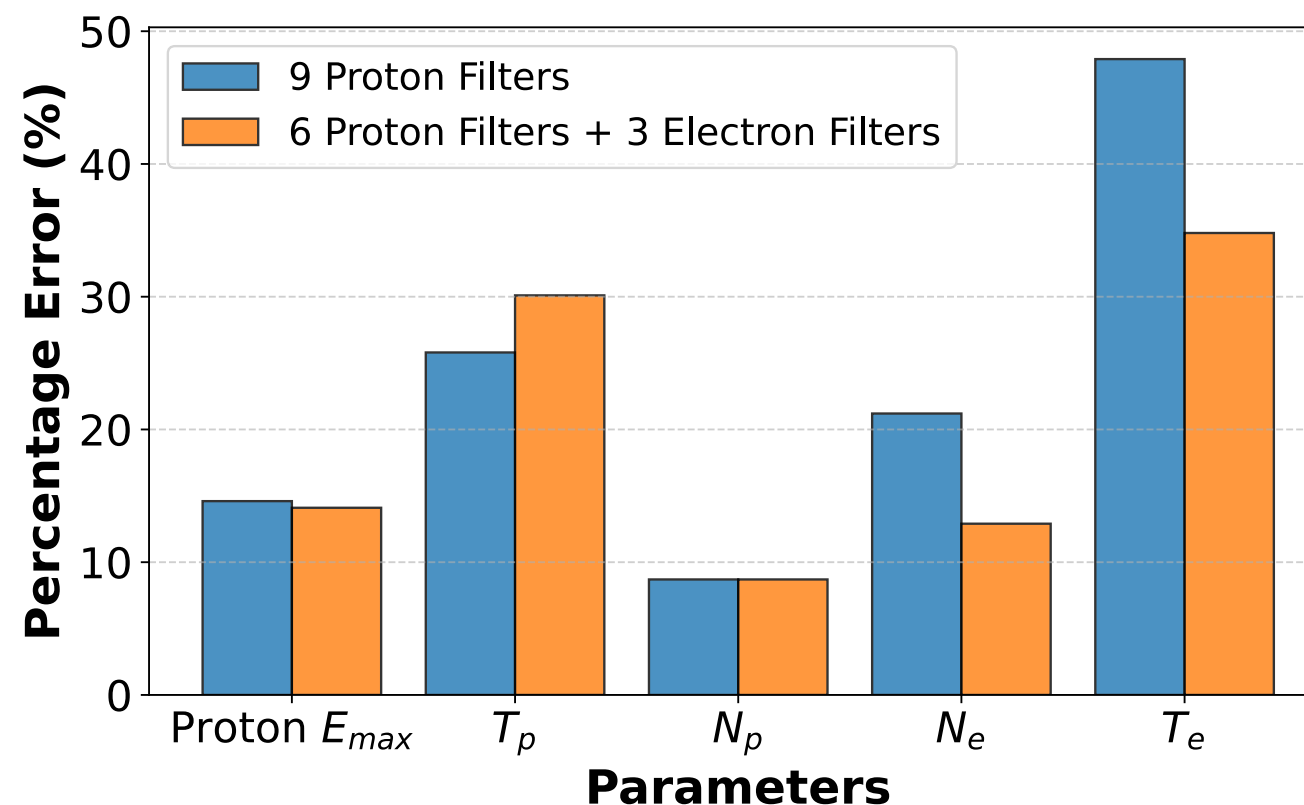
- Repeformed the optimisation loop including electrons
- Electron number & temperature varied randomly for each image
- Significant decrease in accuracy of prediction of maximum energy & temperature



Can we extract electron parameters from the diagnostic?

- Convolutional neural network asked to output electron parameters
- Re-ran filter optimisation including electrons in loss function

$$\frac{dN}{dE} = \begin{cases} N_p \exp(-E/T_p) & \text{for } E \leq E_{max} \\ 0 & \text{for } E > E_{max} \end{cases} \quad \text{Protons}$$
$$\frac{dN}{dE} = N_e \exp(-E/T_e) \quad \text{Electrons}$$



- New design includes *thicker* filters which only see electrons - allowing direct measurement of the 'background'

Conclusion & next steps

- Built workflow for designing & analysing 'PROBIES' diagnostic
 - Optimal filter configuration
 - Extremely quick analysis
 - Robustness to background
- Extended capability to provide electron measurement “for free” (which can be improved!)
- Of course, needs to be implemented experimentally!
- **Workflow transferrable to wide range of particle and radiation diagnostics**